March 2008



FDMA1023PZ

Dual P-Channel PowerTrench® MOSFET

-20V, -3.7A, 72mΩ

Features

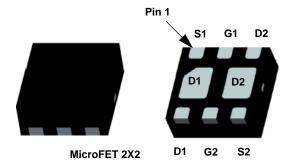
- Max $r_{DS(on)} = 72m\Omega$ at $V_{GS} = -4.5V$, $I_D = -3.7A$
- Max $r_{DS(on)} = 95m\Omega$ at $V_{GS} = -2.5V$, $I_D = -3.2A$
- Max $r_{DS(on)} = 130 \text{m}\Omega$ at $V_{GS} = -1.8 \text{V}$, $I_D = -2.0 \text{A}$
- Max $r_{DS(on)} = 195m\Omega$ at $V_{GS} = -1.5V$, $I_D = -1.0A$
- Low profile 0.8 mm maximum in the new package MicroFET 2x2 mm
- HBM ESD protection level > 2kV typical (Note 3)
- RoHS Compliant

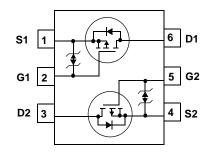


General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connected in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and is well suited to linear mode applications.





MOSFET Maximum Ratings T_A = 25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DS}	Drain to Source Voltage		-20	V
V_{GS}	Gate to Source Voltage		±8	V
1	Drain Current -Continuous	(Note 1a)	-3.7	۸
'D	-Pulsed		-6	A
В	Power Dissipation	(Note 1a)	1.5	W
P_{D}		(Note 1b)	0.7	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1a)	86	
$R_{\theta JA}$	Thermal Resistance for Single Operation, Junction to Ambient	(Note 1b)	173	°C/W
$R_{\theta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1c)	69	*C/VV
$R_{\theta JA}$	Thermal Resistance for Dual Operation, Junction to Ambient	(Note 1d)	151	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
023	FDMA1023PZ	MicroFET 2X2	7"	8mm	3000 units

Electrical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = -250 \mu A, V_{GS} = 0 V$	-20			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		-11		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16V, \ V_{GS} = 0V$			-1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 8V$, $V_{DS} = 0V$			±10	μΑ

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-0.4	-0.7	-1.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$, referenced to 25°C		2.5		mV/°C
		$V_{GS} = -4.5V, I_D = -3.7A$		60	72	
		$V_{GS} = -2.5V$, $I_D = -3.2A$		75	95	
r _{DS(on)}	Static Drain to Source On-Resistance	$V_{GS} = -1.8V$, $I_D = -2.0A$		100	130	mΩ
		$V_{GS} = -1.5V, I_D = -1.0A$		130	195	
		$V_{GS} = -4.5V$, $I_D = -3.7A$, $T_J = 125$ °C		81	91	
9 _{FS}	Forward Transconductance	$V_{DS} = -5V, I_{D} = -3.7A$		12		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 10V V 0V	490	655	pF
C _{oss}	Output Capacitance	$V_{DS} = -10V, V_{GS} = 0V,$ f = 1MHz	100	135	pF
C _{rss}	Reverse Transfer Capacitance	1 - 11VII 12	90	135	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		9	18	ns
t _r	Rise Time	$V_{DD} = -10V, I_D = -1A$ $V_{GS} = -4.5V, R_{GEN} = 6\Omega$	12	22	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5V, R_{GEN} = 0.22$	64	103	ns
t _f	Fall Time		37	60	ns
$Q_{g(TOT)}$	Total Gate Charge	$V_{DD} = -10V, I_D = -3.7A$	8.6	12	nC
Q_{gs}	Gate to Source Gate Charge	V _{GS} = -4.5V	0.7		nC
Q_{gd}	Gate to Drain "Miller" Charge		2.0		nC

Drain-Source Diode Characteristics

IS	Maximum Continuous Drain-Source Diode Forward Current				-1.1	Α
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0V, I_S = -1.1A$ (Note 2)		-0.8	-1.2	V
t _{rr}	Reverse Recovery Time	I = 2.74 di/dt = 1004/		32	48	ns
Q _{rr}	Reverse Recovery Charge	$I_F = -3.7A$, di/dt = 100A/ μ s		15	23	nC

Notes:

- 1: R_{BJA} is determined with the device mounted on a 1 in² oz. copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{BJC} is guaranteed by design while R_{BJA} is determined by the user's board design.

 (a) $R_{\text{BJA}} = 86^{\circ}\text{C/W}$ when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB. For single operation.

 - (b) $R_{\theta JA}$ = 173°C/W when mounted on a minimum pad of 2 oz copper. For single operation.
 - (c) $R_{\theta JA} = 69^{\circ}$ C/W when mounted on a 1in² pad of 2 oz copper, 1.5" x 1.5" x 0.062" thick PCB, For dual operation.
 - (d) $R_{\theta JA} = 151^{\circ}$ C/W when mounted on a minimum pad of 2 oz copper. For dual operation.



- 2: Pulse Test : Pulse Width < 300us, Duty Cycle < 2.0%
- 3: The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics $T_J = 25^{\circ}C$ unless otherwise noted

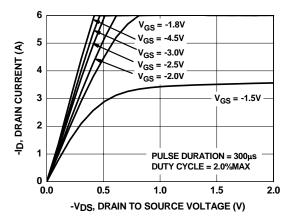


Figure 1. On Region Characteristics

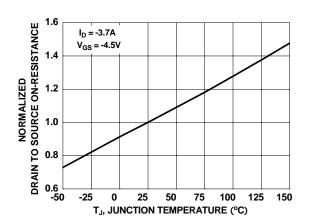


Figure 3. Normalized On-Resistance vs Junction Temperature

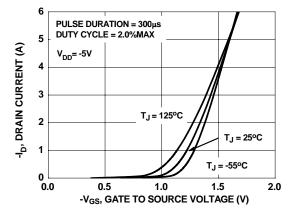


Figure 5. Transfer Characteristics

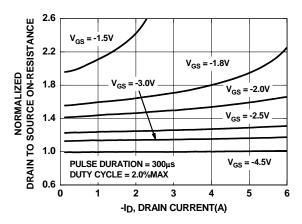


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

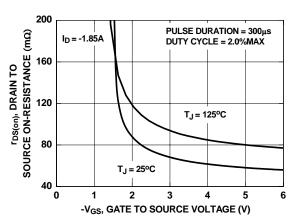


Figure 4. On-Resistance vs Gate to Source Voltage

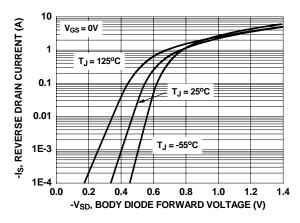


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics T_J = 25°C unless otherwise noted

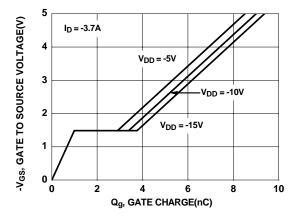


Figure 7. Gate Charge Characteristics

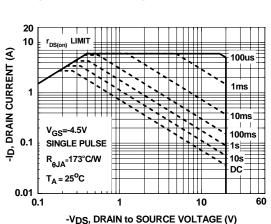


Figure 9. Forward Bias Safe Operating Area

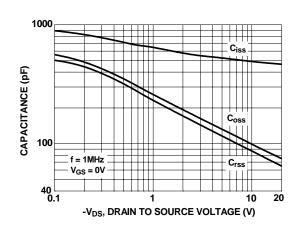


Figure 8. Capacitance Characteristics

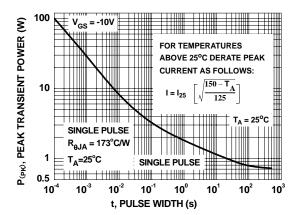


Figure 10. Single Pulse Maximum Power Dissipation

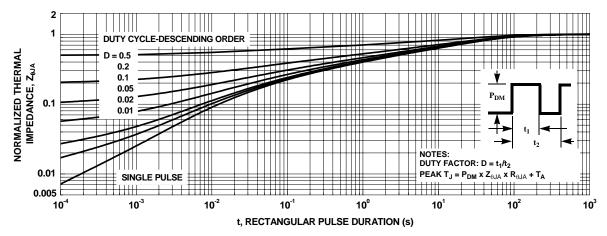
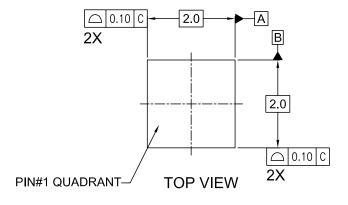
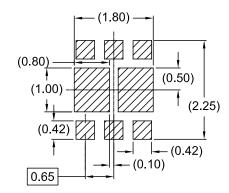


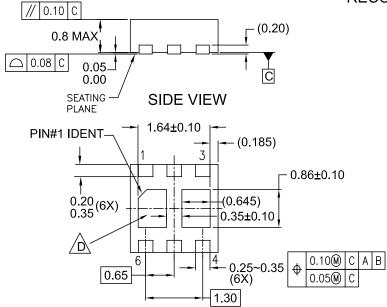
Figure 11. Transient Thermal Response Curve

Dimensional Outline and Pad Layout





RECOMMENDED LAND PATTERN



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- NON-JEDEC DUAL DAP
- E. DRAWING FILE NAME : MLP06J rev3





TRADEMARKS

The following includes registered and unregistered trademarks and service marks, owned by Fairchild Semiconductor and/or its global subsidianries, and is not intended to be an exhaustive list of all such trademarks.

ACEx [®]	FPS™	PDP-SPM™	The Power Franchise®
Build it Now™	F-PFS™	Power-SPM™	puwer
CorePLUS™	FRFET®	PowerTrench [®]	p wer franchise
CorePOWER™	Global Power Resource SM	Programmable Active Droop™	TinyBoost™
CROSSVOLT™	Green FPS™	QFET [®]	TinyBuck™
CTL™	Green FPS™ e-Series™	QS™	TinyLogic [®]
Current Transfer Logic™	GTO™	Quiet Series™	TINYOPTO™
EcoSPARK [®]	IntelliMAX™	RapidConfigure™	TinyPower™
EfficentMax™	ISOPLANAR™	Saving our world 1mW at a time™	TinyPWM™
EZSWITCH™ *	MegaBuck™	SmartMax™	TinyWire™
E Z. ***	MICROCOUPLER™	SMART START™	µSerDes™
	MicroFET™	SPM [®]	\mathcal{U}
F ®	MicroPak™	STEALTH™	Ser Des [™]
[₱] airchild [®]	MillerDrive™	SuperFET™	UHC [®]
Fairchild Semiconductor®	MotionMax™	SuperSOT™-3	Ultra FRFET™
FACT Quiet Series™	Motion-SPM™	SuperSOT™-6	UniFET™
FACT [®]	OPTOLOGIC [®]	SuperSOT™-8	VCX™
FAST [®]	OPTOPLANAR [®]	SuperMOS™	VisualMax™
FastvCore™	(1)®	SYSTEM ®	
FlashWriter [®] *		GENERAL	

^{*} EZSWITCH™ and FlashWriter® are trademarks of System General Corporation, used under license by Fairchild Semiconductor.

DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION, OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS. THESE SPECIFICATIONS DO NOT EXPAND THE TERMS OF FAIRCHILD'S WORLDWIDE TERMS AND CONDITIONS, SPECIFICALLY THE WARRANTY THEREIN, WHICH COVERS THESE PRODUCTS.

LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION.

As used herein:

- Life support devices or systems are devices or systems which,

 (a) are intended for surgical implant into the body or (b) support or sustain life, and (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury of the user.
- A critical component in any component of a life support, device, or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

PRODUCT STATUS DEFINITIONS

Definition of Terms

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data; supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
Obsolete	Not In Production	This datasheet contains specifications on a product that is discontinued by Fairchild Semiconductor. The datasheet is for reference information only.

Rev. I34